Se	Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
10/708,371	CHAN ET AL.
Examiner	Art Unit
Linh V. Nguyen	2819

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SEARCHED					
Class	Subclass	⁻ Date	Examiner		
330	296,285 286,290	1/27/2007	LN		
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
-	DATE	EXMR
East searched-see printout	1/27/2007	LN
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